

<b>Notice of References Cited</b>	Application/Control No. 10/615,088	Applicant(s)/Patent Under Reexamination YEOH ET AL.	
	Examiner David P. Rashid	Art Unit 2624	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0126299	09-2002	Buchar et al.	358/1.9
*	B	US-6,345,116	02-2002	Kojima et al.	382/167
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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